

# **FDC3616N**

# 100V N-Channel PowerTrench® MOSFET

### **General Description**

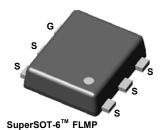
This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low  $R_{\text{DS(ON)}}$  and fast switching speed.

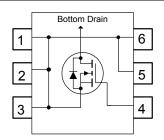
### **Applications**

- DC/DC converter
- · Load Switching

### **Features**

- 3.7 A, 100 V.  $R_{DS(ON)} = 70 \text{ m}\Omega \text{ @ V}_{GS} = 10 \text{ V}$   $R_{DS(ON)} = 80 \text{ m}\Omega \text{ @ V}_{GS} = 6.0 \text{ V}$
- High performance trench technology for extremely low  $R_{\mbox{\scriptsize DS(ON)}}$
- Low gate charge (23nC typical)
- High power and current handling capability
- · Fast switching speed.





### **Absolute Maximum Ratings** T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		100	V
$V_{GSS}$	Gate-Source Voltage		± 20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	3.7	А
	- Pulsed		20	
P <sub>D</sub>	Maximum Power Dissipation	(Note 1a)	2	W
		(Note 1b)	1.1	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C

### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	60	°C/W
		(Note 1b)	111	
R <sub>eJC</sub>	Thermal Resistance, Junction-to-Case		0.5	

**Package Marking and Ordering Information** 

Device Marking	Device	Reel Size	Tape width	Quantity
.616	FDC3616N	7"	8mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-So	ource Avalanche Ratings (Note	2)				•
W <sub>DSS</sub>	Drain-Source Avalanche Energy	Single Pulse, $V_{DD}$ = 50 V, $I_{D}$ = 3.7A			244	mJ
I <sub>AR</sub>	Drain-Source Avalanche Current				3.7	Α
Off Char	acteristics					
BV <sub>DSS</sub>	Drain–Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250 \mu\text{A}$	100			V
<u>ΔBV<sub>DSS</sub></u> ΔΤ <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		114		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V			10	μА
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V			1	μА
I <sub>GSSF</sub>	Gate-Body Leakage, Forward	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V			100	nA
$I_{GSSR}$	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	2.5	4	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		-7.4		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On Resistance	$V_{GS} = 10 \text{ V},  I_D = 3.7 \text{ A}$ $V_{GS} = 6.0 \text{ V},  I_D = 3.5 \text{ A}$ $V_{GS} = 10 \text{ V},  I_D = 3.7 \text{ A},  T_J = 125 ^{\circ}\text{C}$		55 58 104	70 80 139	mΩ
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10 \text{ V},  I_{D} = 3.7 \text{ A}$		19		S
Dvnamio	Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 50 \text{ V},  V_{GS} = 0 \text{ V},$		1215		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		72		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			39		pF
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> = 15 mV, f = 1.0 MHz		1.1		Ω
Switchin	g Characteristics (Note 2)					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 50 \text{ V},  I_D = 1 \text{ A},$		9	18	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V},  R_{GEN} = 6 \Omega$		4	8	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	1		28	45	ns
t <sub>f</sub>	Turn-Off Fall Time	1		10	20	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = 50 \text{ V},  I_D = 3.7 \text{ A},$		23	32	nC
Q <sub>gs</sub>	Gate–Source Charge	V <sub>GS</sub> = 10 V		4.8		nC
$Q_{gd}$	Gate-Drain Charge	1		5.4		nC

## **Electrical Characteristics**

T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Diode Characteristics	and Maximum Ratings				
t <sub>rr</sub>	Diode Reverse Recovery Time	I <sub>F</sub> = 3.7 A,		41		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	$d_{iF}/d_t = 100 \text{ A/}\mu\text{s}$		107		nC
Is	Maximum Continuous Drain-Source Diode Forward Current				2.1	Α
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_S = 2.1 \text{ A}  \text{(Note 2)}$		0.75	1.2	V

#### Notes

1. R<sub>0JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



a) 60°C/W when mounted on a 1in² pad of 2 oz copper



b) 111°C/W when mounted on a minimum pad of 2 oz copper

Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%

# **Typical Characteristics**

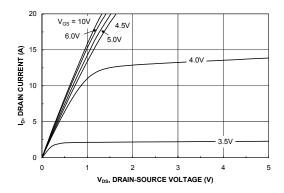


Figure 1. On-Region Characteristics.

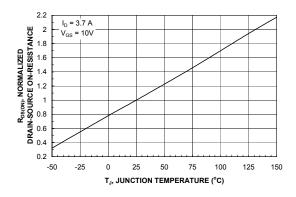


Figure 3. On-Resistance Variation with Temperature.

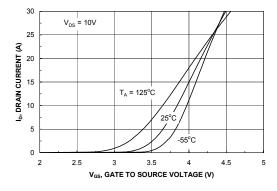


Figure 5. Transfer Characteristics.

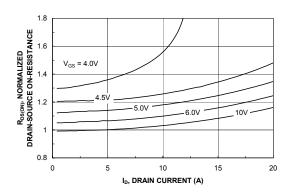


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

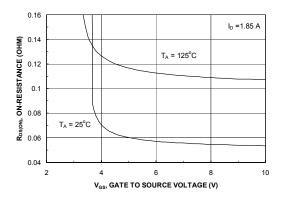


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

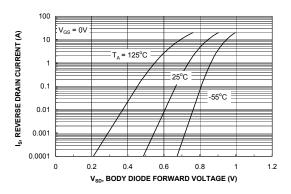
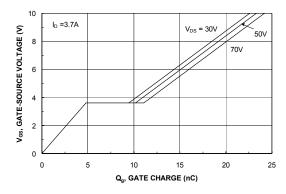


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

# **Typical Characteristics**



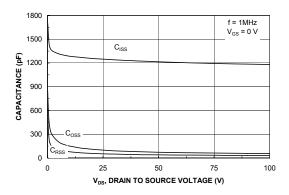
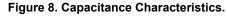
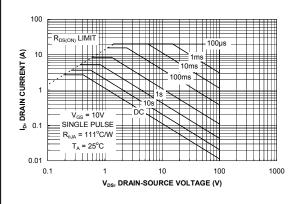


Figure 7. Gate Charge Characteristics.





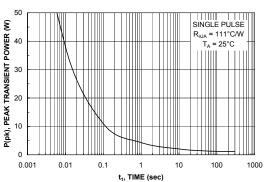


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

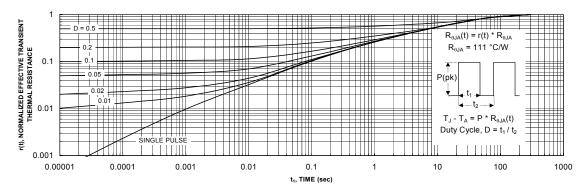


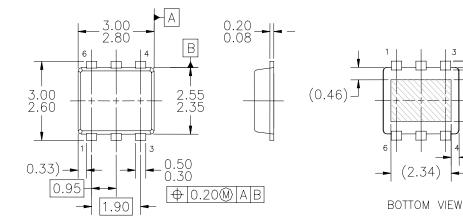
Figure 11. Transient Thermal Response Curve.

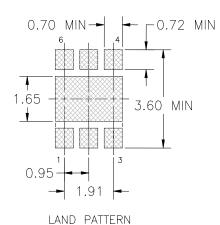
Thermal characterization performed using the conditions described in Note 1b. Transient thermal response will change depending on the circuit board design.

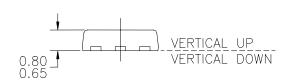
(0.33) \_(0.23)

-(0.31)

# **Dimensional Outline and Pad Layout**







NOTES: UNLESS OTHERWISE SPECIFIED

- A) NO PACKAGE STANDARD REFERENCE AS OF MARCH, 2001.
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE MOLD FLASH AND CUTTING BURRS.
- D) LEAD TIP BURR:

RECOMMENDATION

HORIZONTAL: 0.20 mm MAX VERTICAL UP: 0.20 mm MAX VERTICAL DOWN: 0.05 mm MAX

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CROSSVOLT™	FRFET™	MicroPak™	$QS^{TM}$	SyncFET™
DOME™	GlobalOptoisolator™	MICROWIRE™	QT Optoelectronics™	TinyLogic <sup>®</sup>
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E <sup>2</sup> CMOS™	HiSeC™	MSXPro™	RapidConfigure™	TruTranslation™
EnSigna™	I <sup>2</sup> C <sup>TM</sup>	$OCX^{TM}$	RapidConnect™	UHC™
FACT™	ImpliedDisconnect™	OCXPro™	SILENT SWITCHER®	UltraFET®
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The Power Franchise™		OPTOPLANAR™	SPM <sup>TM</sup>	
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